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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	1825
Number of Logic Elements/Cells	23360
Total RAM Bits	1658880
Number of I/O	150
Number of Gates	-
Voltage - Supply	0.87V ~ 0.93V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 100°C (TJ)
Package / Case	324-LFBGA, CSPBGA
Supplier Device Package	324-CSPBGA (15x15)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc7a25t-l2csg325e

Table 1: Absolute Maximum Ratings⁽¹⁾ (Cont'd)

Symbol	Description	Min	Max	Units
Temperature				
T _{STG}	Storage temperature (ambient)	-65	150	°C
T _{SOL}	Maximum soldering temperature for Pb/Sn component bodies ⁽⁶⁾	-	+220	°C
	Maximum soldering temperature for Pb-free component bodies ⁽⁶⁾	-	+260	°C
T _j	Maximum junction temperature ⁽⁶⁾	-	+125	°C

Notes:

- Stresses beyond those listed under Absolute Maximum Ratings might cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time might affect device reliability.
- The lower absolute voltage specification always applies.
- For I/O operation, refer to [UG471: 7 Series FPGAs SelectIO Resources User Guide](#).
- The maximum limit applied to DC signals.
- For maximum undershoot and overshoot AC specifications, see [Table 4](#).
- For soldering guidelines and thermal considerations, see [UG475: 7 Series FPGA Packaging and Pinout Specification](#).

Table 2: Recommended Operating Conditions⁽¹⁾⁽²⁾

Symbol	Description	Min	Typ	Max	Units
FPGA Logic					
V _{CCINT}	Internal supply voltage	0.95	1.00	1.05	V
	For -2L (0.9V) devices: internal supply voltage	0.87	0.90	0.93	V
V _{CCAUX}	Auxiliary supply voltage	1.71	1.80	1.89	V
V _{CCBRAM}	Block RAM supply voltage	0.95	1.00	1.05	V
V _{CCO} ⁽³⁾⁽⁴⁾	Supply voltage for 3.3V HR I/O banks	1.14	-	3.465	V
V _{IN} ⁽⁵⁾	I/O input voltage	-0.20	-	V _{CCO} + 0.20	V
	I/O input voltage for V _{REF} and differential I/O standards	-0.20	-	2.625	V
I _{IN} ⁽⁶⁾	Maximum current through any pin in a powered or unpowered bank when forward biasing the clamp diode.	-	-	10	mA
V _{CCBATT} ⁽⁷⁾	Battery voltage	1.0	-	1.89	V
GTP Transceiver					
V _{MGTAVCC} ⁽⁸⁾⁽⁹⁾	Analog supply voltage for the GTP transmitter and receiver circuits	0.97	1.0	1.03	V
V _{MGTAVTT} ⁽⁸⁾⁽⁹⁾	Analog supply voltage for the GTP transmitter and receiver termination circuits	1.17	1.2	1.23	V
XADC					
V _{CCADC}	XADC supply relative to GNDADC	1.71	1.80	1.89	V
V _{REFP}	Externally supplied reference voltage	1.20	1.25	1.30	V

Table 2: Recommended Operating Conditions⁽¹⁾⁽²⁾ (Cont'd)

Symbol	Description	Min	Typ	Max	Units
Temperature					
T_j	Junction temperature operating range for commercial (C) temperature devices	0	—	85	°C
	Junction temperature operating range for extended (E) temperature devices	0	—	100	°C
	Junction temperature operating range for industrial (I) temperature devices	-40	—	100	°C

Notes:

1. All voltages are relative to ground.
2. For the design of the power distribution system consult [UG483, 7 Series FPGAs PCB Design and Pin Planning Guide](#).
3. Configuration data is retained even if V_{CCO} drops to 0V.
4. Includes V_{CCO} of 1.2V, 1.5V, 1.8V, 2.5V, and 3.3V.
5. The lower absolute voltage specification always applies.
6. A total of 200 mA per bank should not be exceeded.
7. V_{CCBATT} is required only when using bitstream encryption. If battery is not used, connect V_{CCBATT} to either ground or V_{CCAUX} .
8. Each voltage listed requires the filter circuit described in [UG482: 7 Series FPGAs GTP Transceiver User Guide](#).
9. Voltages are specified for the temperature range of $T_j = 0^\circ\text{C}$ to $+85^\circ\text{C}$.

Table 3: DC Characteristics Over Recommended Operating Conditions

Symbol	Description	Min	Typ ⁽¹⁾	Max	Units
V_{DRINT}	Data retention V_{CCINT} voltage (below which configuration data might be lost)	0.75	—	—	V
V_{DRI}	Data retention V_{CCAUX} voltage (below which configuration data might be lost)	1.5	—	—	V
I_{REF}	V_{REF} leakage current per pin	—	—	15	μA
I_L	Input or output leakage current per pin (sample-tested)	—	—	15	μA
$C_{IN}^{(2)}$	Die input capacitance at the pad	—	—	8	pF
I_{RPU}	Pad pull-up (when selected) @ $V_{IN} = 0\text{V}$, $V_{CCO} = 3.3\text{V}$	90	—	330	μA
	Pad pull-up (when selected) @ $V_{IN} = 0\text{V}$, $V_{CCO} = 2.5\text{V}$	68	—	250	μA
	Pad pull-up (when selected) @ $V_{IN} = 0\text{V}$, $V_{CCO} = 1.8\text{V}$	34	—	220	μA
	Pad pull-up (when selected) @ $V_{IN} = 0\text{V}$, $V_{CCO} = 1.5\text{V}$	23	—	150	μA
	Pad pull-up (when selected) @ $V_{IN} = 0\text{V}$, $V_{CCO} = 1.2\text{V}$	12	—	120	μA
I_{RPD}	Pad pull-down (when selected) @ $V_{IN} = 3.3\text{V}$	68	—	330	μA
	Pad pull-down (when selected) @ $V_{IN} = 1.8\text{V}$	45	—	180	μA
I_{CCADC}	Analog supply current, analog circuits in powered up state	—	—	25	mA
$I_{BATT}^{(3)}$	Battery supply current	—	—	150	nA
$R_{IN_TERM}^{(4)}$	Thevenin equivalent resistance of programmable input termination to $V_{CCO}/2$ (UNTUNED_SPLIT_40) for commercial (C), and industrial (I), and extended (E) temperature devices	28	40	55	Ω
	Thevenin equivalent resistance of programmable input termination to $V_{CCO}/2$ (UNTUNED_SPLIT_50) for commercial (C), and industrial (I), and extended (E) temperature devices	35	50	65	Ω
	Thevenin equivalent resistance of programmable input termination to $V_{CCO}/2$ (UNTUNED_SPLIT_60) for commercial (C), and industrial (I), and extended (E) temperature devices	44	60	83	Ω

Table 9: Differential SelectIO DC Input and Output Levels

I/O Standard	V _{ICM} ⁽¹⁾			V _{ID} ⁽²⁾			V _{OCM} ⁽³⁾			V _{OD} ⁽⁴⁾		
	V, Min	V, Typ	V, Max	V, Min	V, Typ	V, Max	V, Min	V, Typ	V, Max	V, Min	V, Typ	V, Max
BLVDS_25	0.300	1.200	1.425	0.100	—	—	—	1.250	—	Note 5		
MINI_LVDS_25	0.300	1.200	V _{CCAUX}	0.200	0.400	0.600	1.000	1.200	1.400	0.300	0.450	0.600
PPDS_25	0.200	0.900	V _{CCAUX}	0.100	0.250	0.400	0.500	0.950	1.400	0.100	0.250	0.400
RSDS_25	0.300	0.900	1.500	0.100	0.350	0.600	1.000	1.200	1.400	0.100	0.350	0.600
TMDS_33	2.700	2.965	3.230	0.150	0.675	1.200	V _{CCO} –0.405	V _{CCO} –0.300	V _{CCO} –0.190	0.400	0.600	0.800

Notes:

1. V_{ICM} is the input common mode voltage.
2. V_{ID} is the input differential voltage (Q – \bar{Q}).
3. V_{OCM} is the output common mode voltage.
4. V_{OD} is the output differential voltage (Q – \bar{Q}).
5. V_{OD} for BLVDS will vary significantly depending on topology and loading.

Table 10: Complementary Differential SelectIO DC Input and Output Levels

I/O Standard	V _{ICM} ⁽¹⁾			V _{ID} ⁽²⁾		V _{OL} ⁽³⁾		V _{OH} ⁽⁴⁾		I _{OL}	I _{OH}
	V, Min	V, Typ	V, Max	V, Min	V, Max	V, Max	V, Min	mA, Max	mA, Min		
DIFF_HSTL_I	0.300	0.750	1.125	0.100	—	0.400	V _{CCO} –0.400	8.00	–8.00		
DIFF_HSTL_I_18	0.300	0.900	1.425	0.100	—	0.400	V _{CCO} –0.400	8.00	–8.00		
DIFF_HSTL_II	0.300	0.750	1.125	0.100	—	0.400	V _{CCO} –0.400	16.00	–16.00		
DIFF_HSTL_II_18	0.300	0.900	1.425	0.100	—	0.400	V _{CCO} –0.400	16.00	–16.00		
DIFF_HSUL_12	0.300	0.600	0.850	0.100	—	20% V _{CCO}	80% V _{CCO}	0.100	–0.100		
DIFF_MOBILE_DDR	0.300	0.900	1.425	0.100	—	10% V _{CCO}	90% V _{CCO}	0.100	–0.100		
DIFF_SSTL135	0.300	0.675	1.000	0.100	—	(V _{CCO} /2) – 0.150	(V _{CCO} /2) + 0.150	13.0	–13.0		
DIFF_SSTL135_R	0.300	0.675	1.000	0.100	—	(V _{CCO} /2) – 0.150	(V _{CCO} /2) + 0.150	8.9	–8.9		
DIFF_SSTL15	0.300	0.750	1.125	0.100	—	(V _{CCO} /2) – 0.175	(V _{CCO} /2) + 0.175	13.0	–13.0		
DIFF_SSTL15_R	0.300	0.750	1.125	0.100	—	(V _{CCO} /2) – 0.175	(V _{CCO} /2) + 0.175	8.9	–8.9		
DIFF_SSTL18_I	0.300	0.900	1.425	0.100	—	(V _{CCO} /2) – 0.470	(V _{CCO} /2) + 0.470	8.00	–8.00		
DIFF_SSTL18_II	0.300	0.900	1.425	0.100	—	(V _{CCO} /2) – 0.600	(V _{CCO} /2) + 0.600	13.4	–13.4		

Notes:

1. V_{ICM} is the input common mode voltage.
2. V_{ID} is the input differential voltage (Q – \bar{Q}).
3. V_{OL} is the single-ended low-output voltage.
4. V_{OH} is the single-ended high-output voltage.

LVDS DC Specifications (LVDS_25)

See [UG471: 7 Series FPGAs SelectIO Resources User Guide](#) for more information on the LVDS_25 standard in the HR I/O banks.

Table 11: LVDS_25 DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.375	2.500	2.625	V
V_{OH}	Output High Voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	–	–	1.675	V
V_{OL}	Output Low Voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	0.700	–	–	V
V_{ODIFF}	Differential Output Voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High	$R_T = 100 \Omega$ across Q and \bar{Q} signals	247	350	600	mV
V_{OCM}	Output Common-Mode Voltage	$R_T = 100 \Omega$ across Q and \bar{Q} signals	1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High		100	350	600	mV
V_{ICM}	Input Common-Mode Voltage		0.300	1.200	1.425	V

AC Switching Characteristics

All values represented in this data sheet are based on the speed specifications in v1.07 from the 14.4/2012.4 device pack for ISE® Design Suite14.4 and Vivado® Design Suite 2012.4 for the -3, -2, -2L (1.0V), and -1 speed grades and v1.05 from the 14.4/2012.4 device pack for the -2L (0.9V) speed grade.

Switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows:

Advance Product Specification

These specifications are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

Preliminary Product Specification

These specifications are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

Production Product Specification

These specifications are released once enough production silicon of a particular device family member has been characterized to provide full correlation between specifications and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to Production before faster speed grades.

Testing of AC Switching Characteristics

Internal timing parameters are derived from measuring internal test patterns. All AC switching characteristics are representative of worst-case supply voltage and junction temperature conditions.

For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer and back-annotate to the simulation net list. Unless otherwise noted, values apply to all Artix-7 FPGAs.

Speed Grade Designations

Since individual family members are produced at different times, the migration from one category to another depends completely on the status of the fabrication process for each device. [Table 12](#) correlates the current status of each Artix-7 device on a per speed grade basis.

[Table 12: Artix-7 Device Speed Grade Designations](#)

Device	Speed Grade Designations		
	Advance	Preliminary	Production
XC7A100T	-2L (0.9V)		-3, -2, -2L (1.0V), -1
XC7A200T	-2L (0.9V)		-3, -2, -2L (1.0V), -1

Production Silicon and ISE Software Status

In some cases, a particular family member (and speed grade) is released to production before a speed specification is released with the correct label (Advance, Preliminary, Production). Any labeling discrepancies are corrected in subsequent speed specification releases.

[Table 13](#) lists the production released Artix-7 device, speed grade, and the minimum corresponding supported speed specification version and ISE software revisions. The ISE software and speed specifications listed are the minimum releases required for production. All subsequent releases of software and speed specifications are valid.

[Table 13: Artix-7 Device Production Software and Speed Specification Release](#)

Device	Speed Grade			
	1.0V			0.9V
	-3	-2/-2L	-1	-2L
XC7A100T	ISE 14.4 and Vivado 2012.4 with the 14.4/2012.4 device pack v1.07			
XC7A200T	ISE 14.4 and Vivado 2012.4 with the 14.4/2012.4 device pack v1.07			

Notes:

- Blank entries indicate a device and/or speed grade in advance or preliminary status.

Performance Characteristics

This section provides the performance characteristics of some common functions and designs implemented in Artix-7 devices. The numbers reported here are worst-case values; they have all been fully characterized. These values are subject to the same guidelines as the [AC Switching Characteristics, page 9](#).

Table 14: Networking Applications Interface Performances

Description	Speed Grade				Units	
	1.0V		0.9V			
	-3	-2/-2L	-1	-2L		
SDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 8)	680	680	600	600	Mb/s	
DDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 14)	1250	1250	950	950	Mb/s	
SDR LVDS receiver (SFI-4.1) ⁽¹⁾	680	680	600	600	Mb/s	
DDR LVDS receiver (SPI-4.2) ⁽¹⁾	1250	1250	950	950	Mb/s	

Notes:

- LVDS receivers are typically bounded with certain applications where specific dynamic phase-alignment (DPA) algorithms dominate deterministic performance.

Table 15: Maximum Physical Interface (PHY) Rate for Memory Interfaces⁽¹⁾⁽²⁾

Memory Standard	Speed Grade				Units	
	1.0V		0.9V			
	-3	-2/-2L	-1	-2L		
4:1 Memory Controllers						
DDR3	1066	800	800	800	Mb/s	
DDR3L	800	800	667	667	Mb/s	
DDR2	800	800	667	667	Mb/s	
LPDDR2	667	667	533	533	Mb/s	
2:1 Memory Controllers						
DDR3	800	700	620	620	Mb/s	
DDR3L	800	700	620	620	Mb/s	
DDR2	800	700	620	620	Mb/s	

Notes:

- V_{REF} tracking is required. For more information, see [UG586, 7 Series FPGAs Memory Interface Solutions User Guide](#).
- When using the internal V_{REF} the maximum data rate is 800 Mb/s (400 MHz).

IOB Pad Input/Output/3-State

Table 16 summarizes the values of standard-specific data input delay adjustments, output delays terminating at pads (based on standard) and 3-state delays.

- T_{IOP} is described as the delay from IOB pad through the input buffer to the I-pin of an IOB pad. The delay varies depending on the capability of the SelectIO input buffer.
- T_{IOOP} is described as the delay from the O pin to the IOB pad through the output buffer of an IOB pad. The delay varies depending on the capability of the SelectIO output buffer.
- T_{IOTP} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is disabled. The delay varies depending on the SelectIO capability of the output buffer. In HR I/O banks, the IN_TERM termination turn-on time is always faster than T_{IOTP} when the INTERMDISABLE pin is used.

Table 16: 3.3V IOB High Range (HR) Switching Characteristics

I/O Standard	T_{IOP}				T_{IOOP}				T_{IOTP}				Units	
	Speed Grade				Speed Grade				Speed Grade					
	1.0V		0.9V		1.0V		0.9V		1.0V		0.9V			
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L		
LVTTL_S4	1.26	1.34	1.41	1.58	3.80	3.93	4.18	4.41	4.37	4.59	5.01	5.06	ns	
LVTTL_S8	1.26	1.34	1.41	1.58	3.54	3.66	3.92	4.15	4.11	4.32	4.75	4.80	ns	
LVTTL_S12	1.26	1.34	1.41	1.58	3.52	3.65	3.90	4.13	4.09	4.31	4.73	4.78	ns	
LVTTL_S16	1.26	1.34	1.41	1.58	3.07	3.19	3.45	3.68	3.64	3.85	4.28	4.33	ns	
LVTTL_S24	1.26	1.34	1.41	1.58	3.29	3.41	3.67	3.90	3.86	4.07	4.50	4.55	ns	
LVTTL_F4	1.26	1.34	1.41	1.58	3.26	3.38	3.64	3.86	3.83	4.04	4.46	4.51	ns	
LVTTL_F8	1.26	1.34	1.41	1.58	2.74	2.87	3.12	3.35	3.31	3.52	3.95	4.00	ns	
LVTTL_F12	1.26	1.34	1.41	1.58	2.73	2.85	3.10	3.33	3.29	3.51	3.93	3.98	ns	
LVTTL_F16	1.26	1.34	1.41	1.58	2.55	2.68	2.93	3.16	3.12	3.34	3.76	3.81	ns	
LVTTL_F24	1.26	1.34	1.41	1.58	2.52	2.65	2.90	3.22	3.09	3.31	3.73	3.87	ns	
LVDS_25	0.73	0.81	0.88	0.90	1.29	1.41	1.67	1.86	1.86	2.07	2.49	2.51	ns	
MINI_LVDS_25	0.73	0.81	0.88	0.90	1.27	1.40	1.65	1.88	1.84	2.06	2.48	2.53	ns	
BLVDS_25	0.73	0.81	0.88	0.90	1.84	1.96	2.21	2.44	2.40	2.62	3.04	3.09	ns	
RSDS_25 (point to point)	0.73	0.81	0.88	0.90	1.27	1.40	1.65	1.88	1.84	2.06	2.48	2.53	ns	
PPDS_25	0.73	0.81	0.88	0.90	1.29	1.41	1.67	1.88	1.86	2.07	2.49	2.53	ns	
TMDS_33	0.73	0.81	0.88	0.90	1.41	1.54	1.79	1.99	1.98	2.20	2.62	2.64	ns	
PCI33_3	1.24	1.32	1.39	1.57	3.10	3.22	3.48	3.71	3.67	3.88	4.31	4.36	ns	
HSUL_12	0.67	0.75	0.82	0.87	1.80	1.93	2.18	2.41	2.37	2.59	3.01	3.06	ns	
DIFF_HSUL_12	0.68	0.76	0.83	0.88	1.80	1.93	2.18	2.21	2.37	2.59	3.01	2.86	ns	
HSTL_I_S	0.67	0.75	0.82	0.87	1.62	1.74	1.99	2.19	2.19	2.40	2.82	2.84	ns	
HSTL_II_S	0.65	0.73	0.80	0.85	1.41	1.54	1.79	1.99	1.98	2.20	2.62	2.64	ns	
HSTL_I_18_S	0.67	0.75	0.82	0.87	1.29	1.41	1.67	1.86	1.86	2.07	2.49	2.51	ns	
HSTL_II_18_S	0.66	0.75	0.81	0.87	1.41	1.54	1.79	1.97	1.98	2.20	2.62	2.62	ns	
DIFF_HSTL_I_S	0.68	0.76	0.83	0.85	1.59	1.71	1.96	2.13	2.15	2.37	2.79	2.78	ns	
DIFF_HSTL_II_S	0.68	0.76	0.83	0.85	1.51	1.63	1.88	2.07	2.08	2.29	2.71	2.72	ns	
DIFF_HSTL_I_18_S	0.71	0.79	0.86	0.87	1.38	1.51	1.76	1.96	1.95	2.17	2.59	2.61	ns	
DIFF_HSTL_II_18_S	0.70	0.78	0.85	0.87	1.46	1.58	1.84	2.00	2.03	2.24	2.67	2.65	ns	
HSTL_I_F	0.67	0.75	0.82	0.87	1.10	1.22	1.48	1.69	1.67	1.88	2.31	2.34	ns	

Table 16: 3.3V IOB High Range (HR) Switching Characteristics (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units	
	Speed Grade				Speed Grade				Speed Grade					
	1.0V		0.9V		1.0V		0.9V		1.0V		0.9V			
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L		
HSTL_II_F	0.65	0.73	0.80	0.85	1.12	1.24	1.49	1.71	1.69	1.90	2.32	2.36	ns	
HSTL_I_18_F	0.67	0.75	0.82	0.87	1.13	1.26	1.51	1.72	1.70	1.92	2.34	2.37	ns	
HSTL_II_18_F	0.66	0.75	0.81	0.87	1.12	1.24	1.49	1.71	1.69	1.90	2.32	2.36	ns	
DIFF_HSTL_I_F	0.68	0.76	0.83	0.85	1.18	1.30	1.56	1.77	1.75	1.96	2.39	2.42	ns	
DIFF_HSTL_II_F	0.68	0.76	0.83	0.85	1.21	1.33	1.59	1.77	1.78	1.99	2.42	2.42	ns	
DIFF_HSTL_I_18_F	0.71	0.79	0.86	0.87	1.21	1.33	1.59	1.77	1.78	1.99	2.42	2.42	ns	
DIFF_HSTL_II_18_F	0.70	0.78	0.85	0.87	1.21	1.33	1.59	1.77	1.78	1.99	2.42	2.42	ns	
LVCMOS33_S4	1.26	1.34	1.41	1.62	3.80	3.93	4.18	4.41	4.37	4.59	5.01	5.06	ns	
LVCMOS33_S8	1.26	1.34	1.41	1.62	3.52	3.65	3.90	4.13	4.09	4.31	4.73	4.78	ns	
LVCMOS33_S12	1.26	1.34	1.41	1.62	3.09	3.21	3.46	3.69	3.65	3.87	4.29	4.34	ns	
LVCMOS33_S16	1.26	1.34	1.41	1.62	3.40	3.52	3.77	4.00	3.97	4.18	4.60	4.65	ns	
LVCMOS33_F4	1.26	1.34	1.41	1.62	3.26	3.38	3.64	3.86	3.83	4.04	4.46	4.51	ns	
LVCMOS33_F8	1.26	1.34	1.41	1.62	2.74	2.87	3.12	3.35	3.31	3.52	3.95	4.00	ns	
LVCMOS33_F12	1.26	1.34	1.41	1.62	2.55	2.68	2.93	3.16	3.12	3.34	3.76	3.81	ns	
LVCMOS33_F16	1.26	1.34	1.41	1.62	2.55	2.68	2.93	3.16	3.12	3.34	3.76	3.81	ns	
LVCMOS25_S4	1.12	1.20	1.27	1.43	3.13	3.26	3.51	3.72	3.70	3.91	4.34	4.37	ns	
LVCMOS25_S8	1.12	1.20	1.27	1.43	2.88	3.01	3.26	3.49	3.45	3.67	4.09	4.14	ns	
LVCMOS25_S12	1.12	1.20	1.27	1.43	2.48	2.60	2.85	3.08	3.05	3.26	3.68	3.73	ns	
LVCMOS25_S16	1.12	1.20	1.27	1.43	2.82	2.94	3.20	3.43	3.39	3.60	4.03	4.08	ns	
LVCMOS25_F4	1.12	1.20	1.27	1.43	2.74	2.87	3.12	3.35	3.31	3.52	3.95	4.00	ns	
LVCMOS25_F8	1.12	1.20	1.27	1.43	2.18	2.30	2.56	2.79	2.75	2.96	3.39	3.44	ns	
LVCMOS25_F12	1.12	1.20	1.27	1.43	2.16	2.29	2.54	2.77	2.73	2.95	3.37	3.42	ns	
LVCMOS25_F16	1.12	1.20	1.27	1.43	2.01	2.13	2.39	2.61	2.58	2.79	3.21	3.26	ns	
LVCMOS18_S4	0.74	0.83	0.89	0.94	1.62	1.74	1.99	2.19	2.19	2.40	2.82	2.84	ns	
LVCMOS18_S8	0.74	0.83	0.89	0.94	2.18	2.30	2.56	2.79	2.75	2.96	3.39	3.44	ns	
LVCMOS18_S12	0.74	0.83	0.89	0.94	2.18	2.30	2.56	2.79	2.75	2.96	3.39	3.44	ns	
LVCMOS18_S16	0.74	0.83	0.89	0.94	1.52	1.65	1.90	2.13	2.09	2.31	2.73	2.78	ns	
LVCMOS18_S24	0.74	0.83	0.89	0.94	1.60	1.72	1.98	2.21	2.17	2.38	2.81	2.86	ns	
LVCMOS18_F4	0.74	0.83	0.89	0.94	1.45	1.57	1.82	2.05	2.01	2.23	2.65	2.70	ns	
LVCMOS18_F8	0.74	0.83	0.89	0.94	1.68	1.80	2.06	2.29	2.25	2.46	2.89	2.94	ns	
LVCMOS18_F12	0.74	0.83	0.89	0.94	1.68	1.80	2.06	2.29	2.25	2.46	2.89	2.94	ns	
LVCMOS18_F16	0.74	0.83	0.89	0.94	1.40	1.52	1.77	2.00	1.97	2.18	2.60	2.65	ns	
LVCMOS18_F24	0.74	0.83	0.89	0.94	1.34	1.46	1.71	1.94	1.90	2.12	2.54	2.59	ns	
LVCMOS15_S4	0.77	0.86	0.93	0.98	2.05	2.18	2.43	2.50	2.62	2.84	3.26	3.15	ns	
LVCMOS15_S8	0.77	0.86	0.93	0.98	2.09	2.21	2.46	2.69	2.65	2.87	3.29	3.34	ns	
LVCMOS15_S12	0.77	0.86	0.93	0.98	1.59	1.71	1.96	2.19	2.15	2.37	2.79	2.84	ns	
LVCMOS15_S16	0.77	0.86	0.93	0.98	1.59	1.71	1.96	2.19	2.15	2.37	2.79	2.84	ns	

Output Serializer/Deserializer Switching Characteristics

Table 21: OSERDES Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
Setup/Hold						
T _{OSDCK_D} /T _{OSCKD_D}	D input setup/hold with respect to CLKDIV	0.42/0.03	0.45/0.03	0.63/0.03	0.44/-0.25	ns
T _{OSDCK_T} /T _{OSCKD_T} ⁽¹⁾	T input setup/hold with respect to CLK	0.69/-0.13	0.73/-0.13	0.88/-0.13	0.60/-0.25	ns
T _{OSDCK_T2} /T _{OSCKD_T2} ⁽¹⁾	T input setup/hold with respect to CLKDIV	0.31/-0.13	0.34/-0.13	0.39/-0.13	0.46/-0.25	ns
T _{oscck_oce} /T _{osckc_oce}	OCE input setup/hold with respect to CLK	0.32/0.58	0.34/0.58	0.51/0.58	0.21/-0.15	ns
T _{oscck_s}	SR (reset) input setup with respect to CLKDIV	0.47	0.52	0.85	0.70	ns
T _{oscck_tce} /T _{osckc_tce}	TCE input setup/hold with respect to CLK	0.32/0.01	0.34/0.01	0.51/0.01	0.22/-0.15	ns
Sequential Delays						
T _{oscko_oq}	Clock to out from CLK to OQ	0.40	0.42	0.48	0.54	ns
T _{oscko_tq}	Clock to out from CLK to TQ	0.47	0.49	0.56	0.63	ns
Combinatorial						
T _{osdo_ttq}	T input to TQ Out	0.83	0.92	1.11	1.18	ns

Notes:

- T_{OSDCK_T2} and T_{OSCKD_T2} are reported as T_{OSDCK_T}/T_{OSCKD_T} in TRACE report.

Table 27: Block RAM and FIFO Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
T _{RCKC_RSTRAM} /T _{RCKC_RSTRAM}	Synchronous RSTRAM input	0.32/0.42	0.34/0.43	0.36/0.46	0.40/0.47	ns, Min
T _{RCKC_WEA} /T _{RCKC_WEA}	Write enable (WE) input (block RAM only)	0.44/0.18	0.48/0.19	0.54/0.20	0.64/0.23	ns, Min
T _{RCKC_WREN} /T _{RCKC_WREN}	WREN FIFO inputs	0.46/0.30	0.46/0.35	0.47/0.43	0.77/0.44	ns, Min
T _{RCKC_RDEN} /T _{RCKC_RDEN}	RDEN FIFO inputs	0.42/0.30	0.43/0.35	0.43/0.43	0.71/0.44	ns, Min
Reset Delays						
T _{RCO_FLAGS}	Reset RST to FIFO flags/pointers ⁽¹⁰⁾	0.90	0.98	1.10	1.25	ns, Max
T _{RREC_RST} /T _{RREM_RST}	FIFO reset recovery and removal timing ⁽¹¹⁾	1.87/-0.81	2.07/-0.81	2.37/-0.81	2.44/-0.71	ns, Max
Maximum Frequency						
F _{MAX_BRAM_WF_NC}	Block RAM (write first and no change modes) when not in SDP RF mode	509.68	460.83	388.20	315.66	MHz
F _{MAX_BRAM_RF_PERFORMANCE}	Block RAM (read first, performance mode) when in SDP RF mode but no address overlap between port A and port B	509.68	460.83	388.20	315.66	MHz
F _{MAX_BRAM_RF_DELAYED_WRITE}	Block RAM (read first, delayed write mode) when in SDP RF mode and there is possibility of overlap between port A and port B addresses	447.63	404.53	339.67	268.96	MHz
F _{MAX_CAS_WF_NC}	Block RAM cascade (write first, no change mode) when cascade but not in RF mode	467.07	418.59	345.78	273.30	MHz
F _{MAX_CAS_RF_PERFORMANCE}	Block RAM cascade (read first, performance mode) when in cascade with RF mode and no possibility of address overlap/one port is disabled	467.07	418.59	345.78	273.30	MHz
F _{MAX_CAS_RF_DELAYED_WRITE}	When in cascade RF mode and there is a possibility of address overlap between port A and port B	405.35	362.19	297.35	226.60	MHz
F _{MAX_FIFO}	FIFO in all modes without ECC	509.68	460.83	388.20	315.66	MHz
F _{MAX_ECC}	Block RAM and FIFO in ECC configuration	410.34	365.10	297.53	215.38	MHz

Notes:

1. TRACE will report all of these parameters as T_{RCKO_DO}.
2. T_{RCKO_DOR} includes T_{RCKO_DOW}, T_{RCKO_DOPR}, and T_{RCKO_DOPW} as well as the B port equivalent timing parameters.
3. These parameters also apply to synchronous FIFO with DO_REG = 0.
4. T_{RCKO_DO} includes T_{RCKO_DOP} as well as the B port equivalent timing parameters.
5. These parameters also apply to multirate (asynchronous) and synchronous FIFO with DO_REG = 1.
6. T_{RCKO_FLAGS} includes the following parameters: T_{RCKO_AEMPTY}, T_{RCKO_AFULL}, T_{RCKO_EMPTY}, T_{RCKO_FULL}, T_{RCKO_RDERR}, T_{RCKO_WRERR}.
7. T_{RCKO_POINTERS} includes both T_{RCKO_RDCOUNT} and T_{RCKO_WRCOUNT}.
8. The ADDR setup and hold must be met when EN is asserted (even when WE is deasserted). Otherwise, block RAM data corruption is possible.
9. These parameters include both A and B inputs as well as the parity inputs of A and B.
10. T_{RCO_FLAGS} includes the following flags: AEMPTY, AFULL, EMPTY, FULL, RDERR, WRERR, RDCOUNT, and WRCOUNT.
11. RDEN and WREN must be held Low prior to and during reset. The FIFO reset must be asserted for at least five positive clock edges of the slowest clock (WRCLK or RDCLK).

DSP48E1 Switching Characteristics

Table 28: DSP48E1 Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
Setup and Hold Times of Data/Control Pins to the Input Register Clock						
T _{DSPDCK_A_AREG} /T _{DSPCKD_A_AREG}	A input to A register CLK	0.26/ 0.12	0.30/ 0.13	0.37/ 0.14	0.45/ 0.14	ns
T _{DSPDCK_B_BREG} /T _{DSPCKD_B_BREG}	B input to B register CLK	0.33/ 0.15	0.38/ 0.16	0.45/ 0.18	0.60/ 0.19	ns
T _{DSPDCK_C_CREG} /T _{DSPCKD_C_CREG}	C input to C register CLK	0.17/ 0.17	0.20/ 0.19	0.24/ 0.21	0.34/ 0.29	ns
T _{DSPDCK_D_DREG} /T _{DSPCKD_D_DREG}	D input to D register CLK	0.25/ 0.25	0.32/ 0.27	0.42/ 0.27	0.54/ 0.23	ns
T _{DSPDCK_ACIN_AREG} /T _{DSPCKD_ACIN_AREG}	ACIN input to A register CLK	0.23/ 0.12	0.27/ 0.13	0.32/ 0.14	0.36/ 0.14	ns
T _{DSPDCK_BCIN_BREG} /T _{DSPCKD_BCIN_BREG}	BCIN input to B register CLK	0.25/ 0.15	0.29/ 0.16	0.36/ 0.18	0.41/ 0.19	ns
Setup and Hold Times of Data Pins to the Pipeline Register Clock						
T _{DSPDCK_{A,B}_MREG_MULT} / T _{DSPCKD_B_MREG_MULT}	{A, B} input to M register CLK using multiplier	2.40/ -0.01	2.76/ -0.01	3.29/ -0.01	4.31/ -0.07	ns
T _{DSPDCK_{A,B}_ADREG} /T _{DSPCKD_D_ADREG}	{A, D} input to AD register CLK	1.29/ -0.02	1.48/ -0.02	1.76/ -0.02	2.29/ -0.27	ns
Setup and Hold Times of Data/Control Pins to the Output Register Clock						
T _{DSPDCK_{A,B}_PREG_MULT} / T _{DSPCKD_{A,B}_PREG_MULT}	{A, B} input to P register CLK using multiplier	4.02/ -0.28	4.60/ -0.28	5.48/ -0.28	6.95/ -0.48	ns
T _{DSPDCK_D_PREG_MULT} / T _{DSPCKD_D_PREG_MULT}	D input to P register CLK using multiplier	3.93/ -0.73	4.50/ -0.73	5.35/ -0.73	6.73/ -1.68	ns
T _{DSPDCK_{A,B}_PREG} / T _{DSPCKD_{A,B}_PREG}	A or B input to P register CLK not using multiplier	1.73/ -0.28	1.98/ -0.28	2.35/ -0.28	2.80/ -0.48	ns
T _{DSPDCK_C_PREG} / T _{DSPCKD_C_PREG}	C input to P register CLK not using multiplier	1.54/ -0.26	1.76/ -0.26	2.10/ -0.26	2.54/ -0.45	ns
T _{DSPDCK_PCIN_PREG} / T _{DSPCKD_PCIN_PREG}	PCIN input to P register CLK	1.32/ -0.15	1.51/ -0.15	1.80/ -0.15	2.13/ -0.25	ns
Setup and Hold Times of the CE Pins						
T _{DSPDCK_{CEA;CEB}_{AREG;BREG}} / T _{DSPCKD_{CEA;CEB}_{AREG;BREG}}	{CEA; CEB} input to {A; B} register CLK	0.35/ 0.06	0.42/ 0.08	0.52/ 0.11	0.64/ 0.11	ns
T _{DSPDCK_CEC_CREG} /T _{DSPCKD_CEC_CREG}	CEC input to C register CLK	0.28/ 0.10	0.34/ 0.11	0.42/ 0.13	0.49/ 0.16	ns
T _{DSPDCK_CED_DREG} /T _{DSPCKD_CED_DREG}	CED input to D register CLK	0.36/ -0.03	0.43/ -0.03	0.52/ -0.03	0.68/ 0.14	ns
T _{DSPDCK_CEM_MREG} /T _{DSPCKD_CEM_MREG}	CEM input to M register CLK	0.17/ 0.18	0.21/ 0.20	0.27/ 0.23	0.45/ 0.29	ns
T _{DSPDCK_CEP_PREG} /T _{DSPCKD_CEP_PREG}	CEP input to P register CLK	0.36/ 0.01	0.43/ 0.01	0.53/ 0.01	0.63/ 0.00	ns

Table 28: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
Clock to Outs from Pipeline Register Clock to Output Pins						
T _{DSPCKO_P_MREG}	CLK MREG to P output	1.68	1.93	2.31	2.73	ns
T _{DSPCKO_CARRYCASCOU_MREG}	CLK MREG to CARRYCASCOU output	1.92	2.21	2.64	3.12	ns
T _{DSPCKO_P_ADREG_MULT}	CLK ADREG to P output using multiplier	2.72	3.10	3.69	4.60	ns
T _{DSPCKO_CARRYCASCOU_ADREG_MULT}	CLK ADREG to CARRYCASCOU output using multiplier	2.96	3.38	4.02	4.99	ns
Clock to Outs from Input Register Clock to Output Pins						
T _{DSPCKO_P_AREG_MULT}	CLK AREG to P output using multiplier	3.94	4.51	5.37	6.84	ns
T _{DSPCKO_P_BREG}	CLK BREG to P output not using multiplier	1.64	1.87	2.22	2.65	ns
T _{DSPCKO_P_CREG}	CLK CREG to P output not using multiplier	1.69	1.93	2.30	2.81	ns
T _{DSPCKO_P_DREG_MULT}	CLK DREG to P output using multiplier	3.91	4.48	5.32	6.77	ns
Clock to Outs from Input Register Clock to Cascading Output Pins						
T _{DSPCKO_{ACOUT; BCOUT}_{AREG; BREG}}	CLK (ACOUT, BCOUT) to {A,B} register output	0.64	0.73	0.87	1.02	ns
T _{DSPCKO_CARRYCASCOU_{AREG, BREG}_MULT}	CLK (AREG, BREG) to CARRYCASCOU output using multiplier	4.19	4.79	5.70	7.24	ns
T _{DSPCKO_CARRYCASCOU_BREG}	CLK BREG to CARRYCASCOU output not using multiplier	1.88	2.15	2.55	3.04	ns
T _{DSPCKO_CARRYCASCOU_DREG_MULT}	CLK DREG to CARRYCASCOU output using multiplier	4.16	4.76	5.65	7.17	ns
T _{DSPCKO_CARRYCASCOU_CREG}	CLK CREG to CARRYCASCOU output	1.94	2.21	2.63	3.20	ns
Maximum Frequency						
F _{MAX}	With all registers used	628.93	550.66	464.25	363.77	MHz
F _{MAX_PATDET}	With pattern detector	531.63	465.77	392.93	310.08	MHz
F _{MAX_MULT_NOMREG}	Two register multiply without MREG	349.28	305.62	257.47	210.44	MHz
F _{MAX_MULT_NOMREG_PATDET}	Two register multiply without MREG with pattern detect	317.26	277.62	233.92	191.28	MHz
F _{MAX_PREADD_MULT_NOADREG}	Without ADREG	397.30	346.26	290.44	223.26	MHz
F _{MAX_PREADD_MULT_NOADREG_PATDET}	Without ADREG with pattern detect	397.30	346.26	290.44	223.26	MHz
F _{MAX_NOPIPELINEREG}	Without pipeline registers (MREG, ADREG)	260.01	227.01	190.69	150.13	MHz
F _{MAX_NOPIPELINEREG_PATDET}	Without pipeline registers (MREG, ADREG) with pattern detect	241.72	211.15	177.43	140.10	MHz

Table 32: Horizontal Clock Buffer Switching Characteristics (BUFH)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
T_BHCKO_O	BUFH delay from I to O	0.10	0.11	0.13	0.16	ns
T_BHCKC_CE/T_BHCKC_CE	CE pin setup and hold	0.19/0.13	0.22/0.15	0.28/0.21	0.35/0.08	ns
Maximum Frequency						
F_MAX_BUHF	Horizontal clock buffer (BUFH)	628.00	628.00	464.00	394.00	MHz

Table 33: Duty Cycle Distortion and Clock-Tree Skew

Symbol	Description	Device	Speed Grade				Units
			1.0V		0.9V		
			-3	-2/-2L	-1	-2L	
T_DCD_CLK	Global clock tree duty-cycle distortion ⁽¹⁾	All	0.20	0.20	0.20	0.25	ns
T_CKSKEW	Global clock tree skew ⁽²⁾	XC7A100T	0.27	0.33	0.36	0.48	ns
		XC7A200T	0.40	0.48	0.54	0.69	ns
T_DCD_BUFIO	I/O clock tree duty cycle distortion	All	0.14	0.14	0.14	0.14	ns
T_BUFIOSKEW	I/O clock tree skew across one clock region	All	0.03	0.03	0.03	0.03	ns
T_DCD_BUFR	Regional clock tree duty cycle distortion	All	0.18	0.18	0.18	0.18	ns

Notes:

- These parameters represent the worst-case duty cycle distortion observable at the I/O flip flops. For all I/O standards, IBIS can be used to calculate any additional duty cycle distortion that might be caused by asymmetrical rise/fall times.
- The T_CKSKEW value represents the worst-case clock-tree skew observable between sequential I/O elements. Significantly less clock-tree skew exists for I/O registers that are close to each other and fed by the same or adjacent clock-tree branches. Use the Xilinx FPGA_Editor and Timing Analyzer tools to evaluate clock skew specific to your application.

MMCM Switching Characteristics

Table 34: MMCM Specification

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
MMCM_F_INMAX	Maximum input clock frequency	800.00	800.00	800.00	800.00	MHz
MMCM_F_INMIN	Minimum input clock frequency	10.00	10.00	10.00	10.00	MHz
MMCM_F_INJITTER	Maximum input clock period jitter	< 20% of clock input period or 1 ns Max				
MMCM_F_INDUTY	Allowable input duty cycle: 10—49 MHz	25	25	25	25	%
	Allowable input duty cycle: 50—199 MHz	30	30	30	30	%
	Allowable input duty cycle: 200—399 MHz	35	35	35	35	%
	Allowable input duty cycle: 400—499 MHz	40	40	40	40	%
	Allowable input duty cycle: >500 MHz	45	45	45	45	%
MMCM_F_MIN_PSCLK	Minimum dynamic phase-shift clock frequency	0.01	0.01	0.01	0.01	MHz
MMCM_F_MAX_PSCLK	Maximum dynamic phase-shift clock frequency	550.00	500.00	450.00	450.00	MHz
MMCM_F_VCOMIN	Minimum MMCM VCO frequency	600.00	600.00	600.00	600.00	MHz
MMCM_F_VCOMAX	Maximum MMCM VCO frequency	1600.00	1440.00	1200.00	1200.00	MHz

Table 34: MMCM Specification (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
MMCM_F_BANDWIDTH	Low MMCM bandwidth at typical ⁽¹⁾	1.00	1.00	1.00	1.00	MHz
	High MMCM bandwidth at typical ⁽¹⁾	4.00	4.00	4.00	4.00	MHz
MMCM_T_STATPHAOFFSET	Static phase offset of the MMCM outputs ⁽²⁾	0.12	0.12	0.12	0.12	ns
MMCM_T_OUTJITTER	MMCM output jitter	Note 3				
MMCM_T_OUTDUTY	MMCM output clock duty-cycle precision ⁽⁴⁾	0.20	0.20	0.20	0.25	ns
MMCM_T_LOCKMAX	MMCM maximum lock time	100.00	100.00	100.00	100.00	μs
MMCM_F_OUTMAX	MMCM maximum output frequency	800.00	800.00	800.00	800.00	MHz
MMCM_F_OUTMIN	MMCM minimum output frequency ⁽⁵⁾⁽⁶⁾	4.69	4.69	4.69	4.69	MHz
MMCM_T_EXTFDVAR	External clock feedback variation	< 20% of clock input period or 1 ns Max				
MMCM_RST_MINPULSE	Minimum reset pulse width	5.00	5.00	5.00	5.00	ns
MMCM_F_PFDMAX	Maximum frequency at the phase frequency detector	550.00	500.00	450.00	450.00	MHz
MMCM_F_PFDMIN	Minimum frequency at the phase frequency detector	10.00	10.00	10.00	10.00	MHz
MMCM_T_FBDelay	Maximum delay in the feedback path	3 ns Max or one CLKIN cycle				
MMCM Switching Characteristics Setup and Hold						
T_MMCM_DCK_PSEN/ T_MMCM_CKD_PSEN	Setup and hold of phase-shift enable	1.04/0.00	1.04/0.00	1.04/0.00	1.04/0.00	ns
T_MMCM_DCK_PSINCDEC/ T_MMCM_CKD_PSINCDEC	Setup and hold of phase-shift increment/decrement	1.04/0.00	1.04/0.00	1.04/0.00	1.04/0.00	ns
T_MMCM_CKO_PSDONE	Phase shift clock-to-out of PSDONE	0.59	0.68	0.81	0.78	ns
Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK						
T_MMCM_DCK_DADDR/ T_MMCM_CKD_DADDR	DADDR setup/hold	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T_MMCM_DCK_DI/ T_MMCM_CKD_DI	DI setup/hold	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T_MMCM_DCK_DEN/ T_MMCM_CKD_DEN	DEN setup/hold	1.76/0.00	1.97/0.00	2.29/0.00	2.40/0.00	ns, Min
T_MMCM_DCK_DWE/ T_MMCM_CKD_DWE	DWE setup/hold	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T_MMCM_CKO_DRDY	CLK to out of DRDY	0.65	0.72	0.99	0.70	ns, Max
F_DCK	DCLK frequency	200.00	200.00	200.00	100.00	MHz, Max

Notes:

- The MMCM does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
- The static offset is measured between any MMCM outputs with identical phase.
- Values for this parameter are available in the Clocking Wizard.
See http://www.xilinx.com/products/intellectual-property/clocking_wizard.htm.
- Includes global clock buffer.
- Calculated as $F_{VCO}/128$ assuming output duty cycle is 50%.
- When CLKOUT4_CASCADE = TRUE, MMCM_F_OUTMIN is 0.036 MHz.

Table 39: Clock-Capable Clock Input to Output Delay With PLL

Symbol	Description	Device	Speed Grade				Units
			1.0V		0.9V		
			-3	-2/-2L	-1	-2L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, <i>with</i> PLL.							
TICKOFPPLLCC	Clock-capable clock input and OUTFF <i>with</i> PLL	XC7A100T	0.70	0.70	0.70	1.41	ns
		XC7A200T	0.69	0.69	0.69	1.47	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. PLL output jitter is already included in the timing calculation.

Table 40: Pin-to-Pin, Clock-to-Out using BUFI0

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, with BUFI0.						
TICKOFC0	Clock to out of I/O clock	5.01	5.61	6.64	7.34	ns

Device Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. Values are expressed in nanoseconds unless otherwise noted.

Table 41: Global Clock Input Setup and Hold Without MMCM/PLL with ZHOLD_DELAY on HR I/O Banks

Symbol	Description	Device	Speed Grade				Units	
			1.0V		0.9V			
			-3	-2/-2L	-1	-2L		
Input Setup and Hold Time Relative to Global Clock Input Signal for SSTL15 Standard. ⁽¹⁾								
T _{PSFD} / T _{PHFD}	Full delay (legacy delay or default delay) global clock input and IFF ⁽²⁾ without MMCM/PLL with ZHOLD_DELAY on HR I/O banks	XC7A100T	2.69/-0.46	2.89/-0.46	3.34/-0.46	5.66/-0.52	ns	
		XC7A200T	3.03/-0.50	3.27/-0.50	3.79/-0.50	6.66/-0.53	ns	

Notes:

1. Setup and hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the global clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the global clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input flip-flop or latch
3. A zero "0" hold time listing indicates no hold time or a negative hold time.

Table 42: Clock-Capable Clock Input Setup and Hold With MMCM

Symbol	Description	Device	Speed Grade				Units	
			1.0V		0.9V			
			-3	-2/-2L	-1	-2L		
Input Setup and Hold Time Relative to Global Clock Input Signal for SSTL15 Standard. ⁽¹⁾								
T _{PSMMCMCC} / T _{PHMMCMCC}	No delay clock-capable clock input and IFF ⁽²⁾ with MMCM	XC7A100T	2.44/-0.62	2.80/-0.62	3.36/-0.62	2.15/-0.49	ns	
		XC7A200T	2.57/-0.63	2.94/-0.63	3.52/-0.63	2.32/-0.53	ns	

Notes:

1. Setup and hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the global clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the global clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input flip-flop or latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 43: Clock-Capable Clock Input Setup and Hold With PLL

Symbol	Description	Device	Speed Grade				Units	
			1.0V		0.9V			
			-3	-2/-2L	-1	-2L		
Input Setup and Hold Time Relative to Clock-Capable Clock Input Signal for SSTL15 Standard. ⁽¹⁾								
T _{PSPLLCC} / T _{PHPLLCC}	No delay clock-capable clock input and IFF ⁽²⁾ with PLL	XC7A100T	2.78/-0.32	3.15/-0.32	3.78/-0.32	2.47/-0.60	ns	
		XC7A200T	2.91/-0.33	3.29/-0.33	3.94/-0.33	2.64/-0.63	ns	

Notes:

1. Setup and hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the global clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the global clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input flip-flop or latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 44: Data Input Setup and Hold Times Relative to a Forwarded Clock Input Pin Using BUFIO

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
Input Setup and Hold Time Relative to a Forwarded Clock Input Pin Using BUFIO for SSTL15 Standard.						
T _{PSCS} /T _{PHCS}	Setup and hold of I/O clock	-0.38/1.31	-0.38/1.46	-0.38/1.76	-0.16/1.89	ns

Table 45: Sample Window

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
T _{SAMP}	Sampling error at receiver pins ⁽¹⁾	0.59	0.64	0.70	0.70	ns
T _{SAMP_BUFI0}	Sampling error at receiver pins using BUFIO ⁽²⁾	0.35	0.40	0.46	0.46	ns

Notes:

1. This parameter indicates the total sampling error of the Artix-7 FPGAs DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the MMCM to capture the DDR input registers' edges of operation. These measurements include:
 - CLKO MMCM jitter
 - MMCM accuracy (phase offset)
 - MMCM phase shift resolution
 These measurements do not include package or clock tree skew.
2. This parameter indicates the total sampling error of the Artix-7 FPGAs DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the BUFIO clock network and IDELAY to capture the DDR input registers' edges of operation. These measurements do not include package or clock tree skew.

Additional Package Parameter Guidelines

The parameters in this section provide the necessary values for calculating timing budgets for Artix-7 FPGA clock transmitter and receiver data-valid windows.

Table 46: Package Skew

Symbol	Description	Device	Package	Value	Units
T _{PKGSKEW}	Package skew ⁽¹⁾	XC7A100T	CSG324	113	ps
			FTG256	120	ps
			FGG484	144	ps
			FGG676	153	ps
		XC7A200T	SBG484	111	ps
			FBG484	109	ps
			FBG676	121	ps
			FFG1156	151	ps

Notes:

1. These values represent the worst-case skew between any two SelectIO resources in the package: shortest delay to longest delay from die pad to ball.
2. Package delay information is available for these device/package combinations. This information can be used to deskew the package.

Table 48 summarizes the DC specifications of the clock input of the GTP transceiver. Consult [UG482: 7 Series FPGAs GTP Transceiver User Guide](#) for further details.

Table 48: GTP Transceiver Clock DC Input Level Specification

Symbol	DC Parameter	Min	Typ	Max	Units
V_{IDIFF}	Differential peak-to-peak input voltage	350	—	2000	mV
R_{IN}	Differential input resistance	—	100	—	Ω
C_{EXT}	Required external AC coupling capacitor	—	100	—	nF

GTP Transceiver Switching Characteristics

Consult [UG482: 7 Series FPGAs GTP Transceiver User Guide](#) for further information.

Table 49: GTP Transceiver Performance

Symbol	Description	Output Divider	Speed Grade								Units	
			1.0V				0.9V					
			-3		-2/-2L		-1		-2L			
			Package Type									
			FFG FBG SBG	FGG FTG CSG	FFG FBG SBG	FGG FTG CSG	FFG FBG SBG	FGG FTG CSG	FFG FBG SBG	FGG FTG CSG		
F_{GTPMAX}	Maximum GTP transceiver data rate		6.6	5.4	6.6	5.4	3.75	3.75	3.75	3.75	Gb/s	
F_{GTPMIN}	Minimum GTP transceiver data rate		0.500	0.500	0.500	0.500	0.500	0.500	0.500	0.500	Gb/s	
$F_{GTPRANGE}$	PLL line rate range	1	3.2–6.6		3.2–6.6		3.2–3.75		3.2–3.75		Gb/s	
		2	1.6–3.3		1.6–3.3		1.6–3.2		1.6–3.2		Gb/s	
		4	0.8–1.65		0.8–1.65		0.8–1.6		0.8–1.6		Gb/s	
		8	0.5–0.825		0.5–0.825		0.5–0.8		0.5–0.8		Gb/s	
$F_{GTPPLL RANGE}$	GTP transceiver PLL frequency range		1.6–3.3		1.6–3.3		1.6–3.3		1.6–3.3		GHz	

Table 50: GTP Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics

Symbol	Description	Speed Grade				Units	
		1.0V		0.9V			
		-3	-2/-2L	-1	-2L		
$F_{GTPDRPCLK}$	GTPDRPCLK maximum frequency	175	175	156	125	MHz	

Table 51: GTP Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F_{GCLK}	Reference clock frequency range		60	—	660	MHz
T_{RCLK}	Reference clock rise time	20% – 80%	—	200	—	ps
T_{FCLK}	Reference clock fall time	20% – 80%	—	200	—	ps
T_{DCREF}	Reference clock duty cycle	Transceiver PLL only	40	—	60	%

Table 54: GTP Transceiver Transmitter Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
F_{GTPTX}	Serial data rate range		0.500	—	F_{GTPMAX}	Gb/s
T_{RTX}	TX rise time	20%–80%	—	50	—	ps
T_{FTX}	TX fall time	20%–80%	—	50	—	ps
T_{LLSKEW}	TX lane-to-lane skew ⁽¹⁾		—	—	500	ps
$V_{TXOOBVDPDPP}$	Electrical idle amplitude		—	—	20	mV
$T_{TXOOBTTRANSITION}$	Electrical idle transition time		—	—	140	ns
$TJ_{6.6}$	Total Jitter ⁽²⁾⁽³⁾	6.6 Gb/s	—	—	0.30	UI
$DJ_{6.6}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.15	UI
$TJ_{5.0}$	Total Jitter ⁽²⁾⁽³⁾	5.0 Gb/s	—	—	0.30	UI
$DJ_{5.0}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.15	UI
$TJ_{4.25}$	Total Jitter ⁽²⁾⁽³⁾	4.25 Gb/s	—	—	0.30	UI
$DJ_{4.25}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.15	UI
$TJ_{3.75}$	Total Jitter ⁽²⁾⁽³⁾	3.75 Gb/s	—	—	0.30	UI
$DJ_{3.75}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.15	UI
$TJ_{3.2}$	Total Jitter ⁽²⁾⁽³⁾	3.20 Gb/s ⁽⁴⁾	—	—	0.2	UI
$DJ_{3.2}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.1	UI
$TJ_{3.2L}$	Total Jitter ⁽²⁾⁽³⁾	3.20 Gb/s ⁽⁵⁾	—	—	0.32	UI
$DJ_{3.2L}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.16	UI
$TJ_{2.5}$	Total Jitter ⁽²⁾⁽³⁾	2.5 Gb/s ⁽⁶⁾	—	—	0.20	UI
$DJ_{2.5}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.08	UI
$TJ_{1.25}$	Total Jitter ⁽²⁾⁽³⁾	1.25 Gb/s ⁽⁷⁾	—	—	0.15	UI
$DJ_{1.25}$	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.06	UI
TJ_{500}	Total Jitter ⁽²⁾⁽³⁾	500 Mb/s	—	—	0.1	UI
DJ_{500}	Deterministic Jitter ⁽²⁾⁽³⁾		—	—	0.03	UI

Notes:

1. Using same REFCLK input with TX phase alignment enabled for up to four consecutive transmitters (one fully populated GTP Quad).
2. Using PLL[0/1]_FBDIV = 2, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
3. All jitter values are based on a bit-error ratio of $1e^{-12}$.
4. PLL frequency at 3.2 GHz and TXOUT_DIV = 2.
5. PLL frequency at 1.6 GHz and TXOUT_DIV = 1.
6. PLL frequency at 2.5 GHz and TXOUT_DIV = 2.
7. PLL frequency at 2.5 GHz and TXOUT_DIV = 4.

Table 55: GTP Transceiver Receiver Switching Characteristics

Symbol	Description		Min	Typ	Max	Units
F_{GTPRX}	Serial data rate	RX oversampler not enabled	0.500	—	F_{GTPMAX}	Gb/s
$T_{RXELECIDLE}$	Time for RXELECIDLE to respond to loss or restoration of data		—	10	—	ns
RX_{OOBVDP}	OOB detect threshold peak-to-peak		60	—	150	mV
RX_{SST}	Receiver spread-spectrum tracking ⁽¹⁾	Modulated @ 33 KHz	-5000	—	5000	ppm
RX_{RL}	Run length (CID)		—	—	512	UI
RX_{PPMTOL}	Data/REFCLK PPM offset tolerance		-1250	—	1250	ppm
SJ Jitter Tolerance⁽²⁾						
$JT_{SJ6.6}$	Sinusoidal Jitter ⁽³⁾	6.6 Gb/s	0.44	—	—	UI
$JT_{SJ5.0}$	Sinusoidal Jitter ⁽³⁾	5.0 Gb/s	0.44	—	—	UI
$JT_{SJ4.25}$	Sinusoidal Jitter ⁽³⁾	4.25 Gb/s	0.44	—	—	UI
$JT_{SJ3.75}$	Sinusoidal Jitter ⁽³⁾	3.75 Gb/s	0.44	—	—	UI
$JT_{SJ3.2}$	Sinusoidal Jitter ⁽³⁾	3.2 Gb/s ⁽⁴⁾	0.45	—	—	UI
$JT_{SJ3.2L}$	Sinusoidal Jitter ⁽³⁾	3.2 Gb/s ⁽⁵⁾	0.45	—	—	UI
$JT_{SJ2.5}$	Sinusoidal Jitter ⁽³⁾	2.5 Gb/s ⁽⁶⁾	0.5	—	—	UI
$JT_{SJ1.25}$	Sinusoidal Jitter ⁽³⁾	1.25 Gb/s ⁽⁷⁾	0.5	—	—	UI
JT_{SJ500}	Sinusoidal Jitter ⁽³⁾	500 Mb/s	0.4	—	—	UI
SJ Jitter Tolerance with Stressed Eye⁽²⁾						
$JT_{TJSE3.2}$	Total Jitter with Stressed Eye ⁽⁸⁾	3.2 Gb/s	0.70	—	—	UI
$JT_{TJSE6.6}$		6.6 Gb/s	0.70	—	—	UI
$JT_{SJSE3.2}$	Sinusoidal Jitter with Stressed Eye ⁽⁸⁾	3.2 Gb/s	0.1	—	—	UI
$JT_{SJSE6.6}$		6.6 Gb/s	0.1	—	—	UI

Notes:

1. Using RXOUT_DIV = 1, 2, and 4.
2. All jitter values are based on a bit error ratio of $1e^{-12}$.
3. The frequency of the injected sinusoidal jitter is 10 MHz.
4. PLL frequency at 3.2 GHz and RXOUT_DIV = 2.
5. PLL frequency at 1.6 GHz and RXOUT_DIV = 1.
6. PLL frequency at 2.5 GHz and RXOUT_DIV = 2.
7. PLL frequency at 2.5 GHz and RXOUT_DIV = 4.
8. Composite jitter.